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## InAs/AlSb quantum-cascade lasers grown on Silicon

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PW10926-41, SPIE Phot West, Quantum Sensing, February 5, 2019, San Francisco, CA. Proc SPIE **10926**, 1092618 (2019).

# OUTLINE

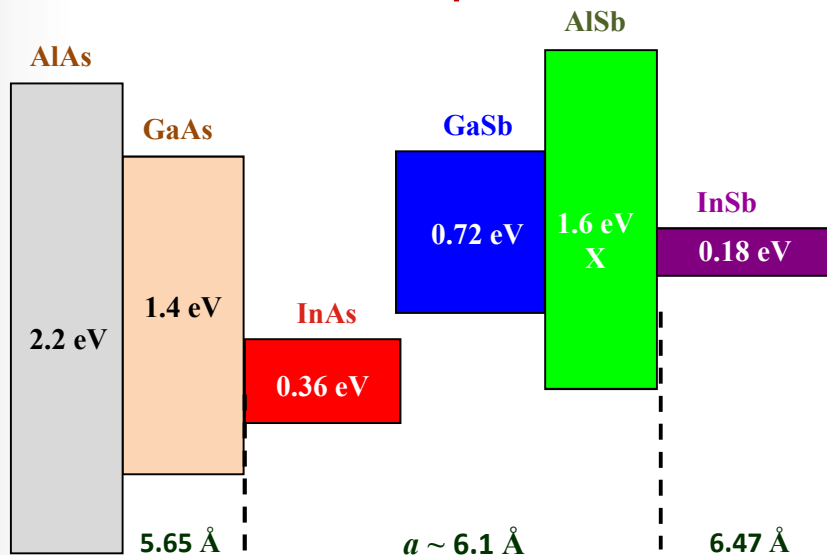
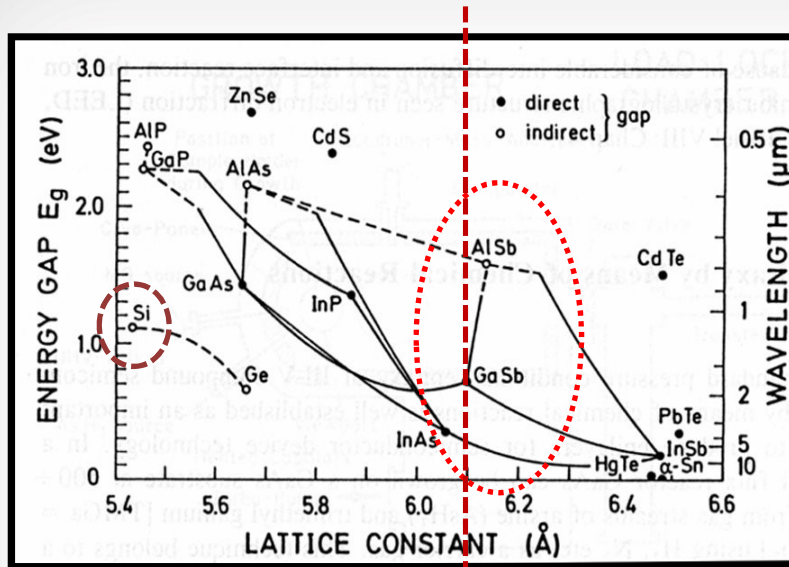
- InAs/AlSb quantum cascade lasers: properties
- Integration on Si: motivations
- Molecular-beam epitaxy on Si
- Laser properties
- Summary – Perspectives

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## Antimonide compound semiconductors

### GaSb, AlSb, InSb, InAs and their alloys



- Large bandgap range:  
0.1 – 1.8 eV
- Various band alignments:  
Type I, Type II, Type III
- Large band offsets:  
 $\Delta E_c = 0 - 2 \text{ eV}$   
 $\Delta E_v = 0 - 0.5 \text{ eV}$

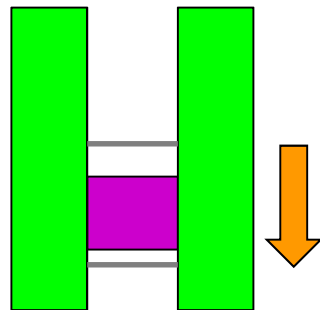
➡ *Unrivalled band structure engineering*

➡ *Mismatch with Si  $\sim 12\%$*

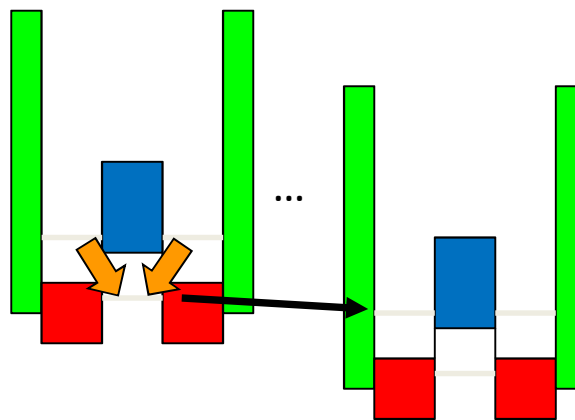
III-Sbs: perfectly suited for the IR wavelength range

# Sb-based IR devices

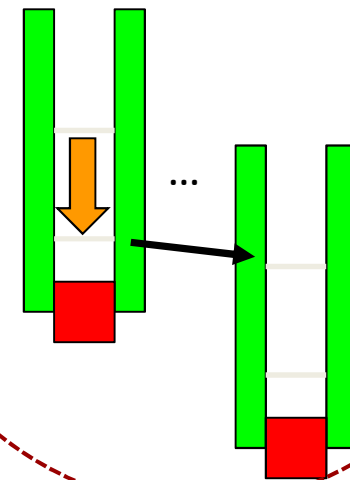
**QW Lasers**  
**GaInAsSb/AlAsSb**



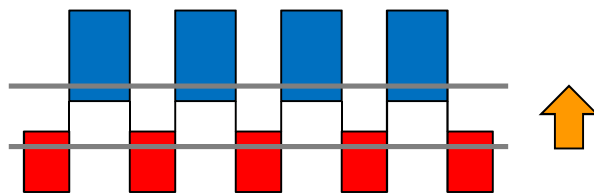
**Interband Cascade Lasers**  
**InAs/GaSb/AlSb**



**Quantum Cascade Lasers**  
**InAs/AlSb**

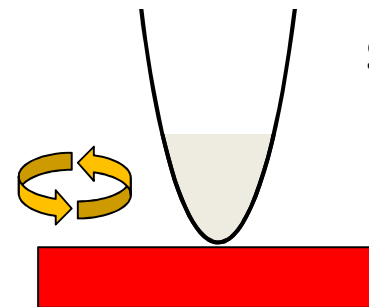


**Type II SL Detectors**  
**InAs/GaSb (or InAs/InAsSb)**

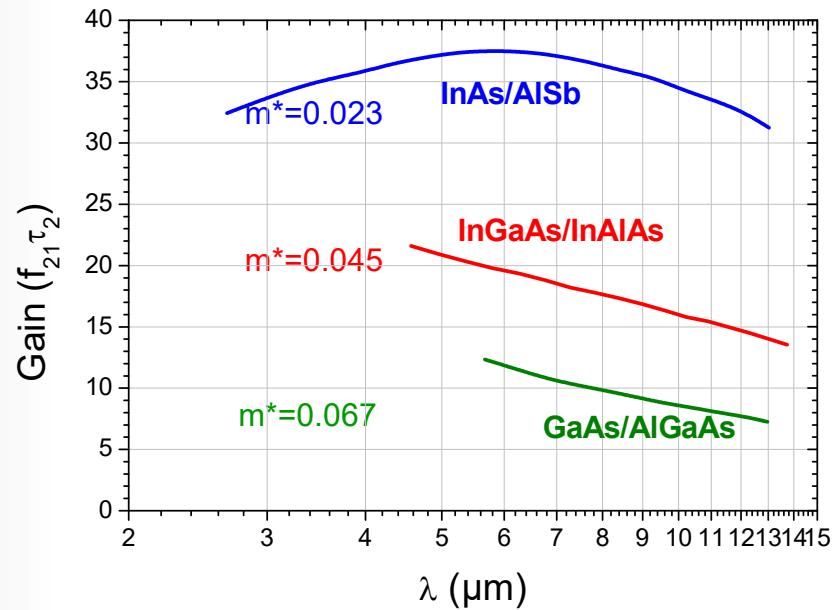


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**SC Plasmonics**  
**InAs(Sb)**

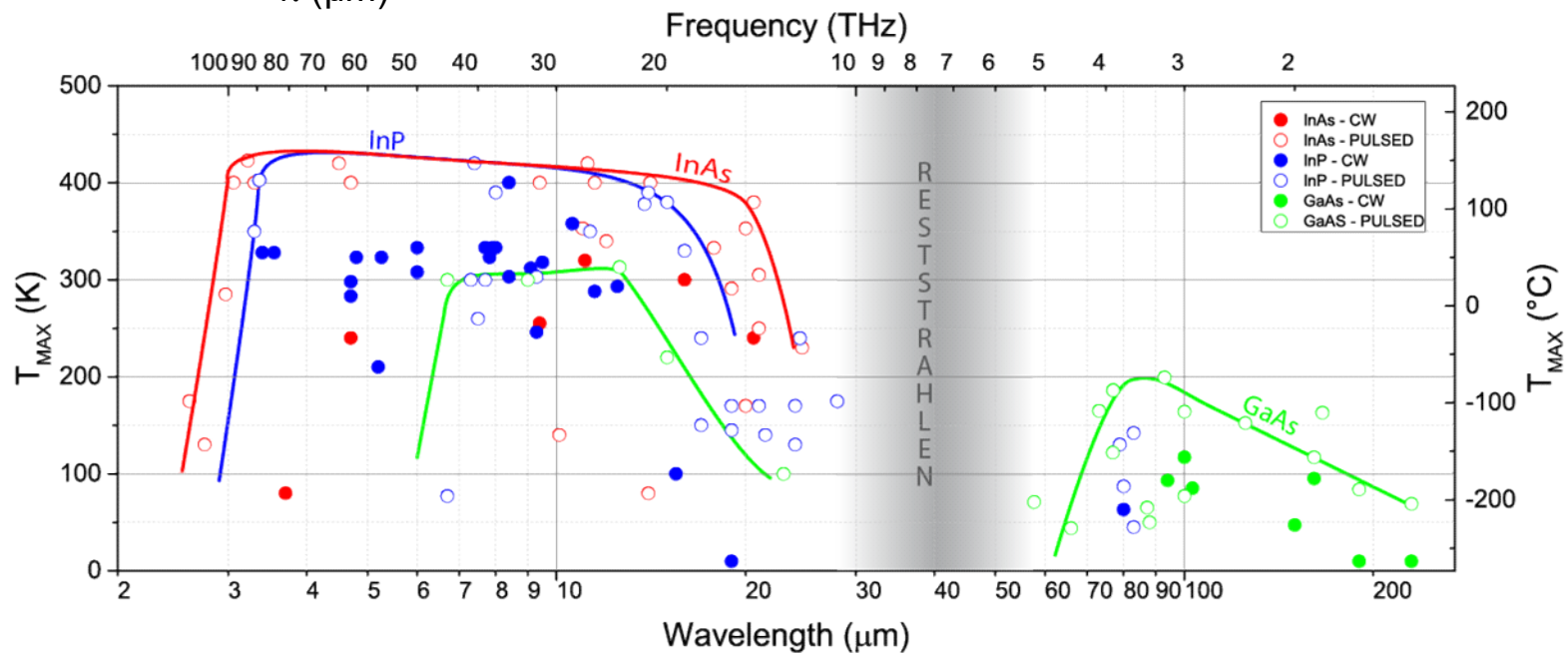


# InAs/AlSb: very good intrinsic properties for QCLs

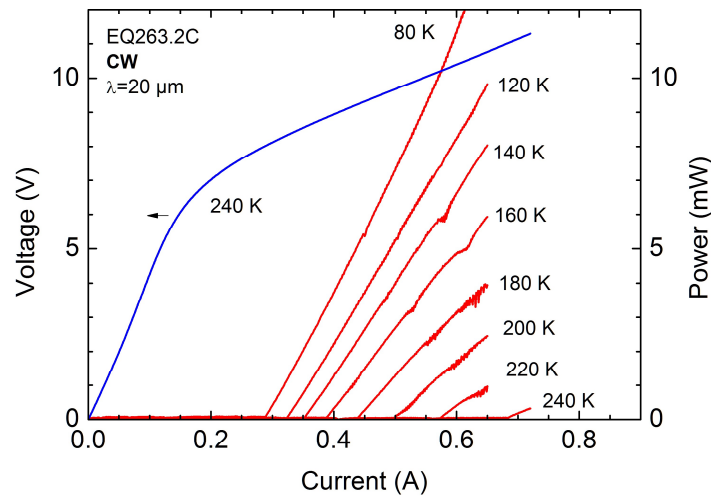
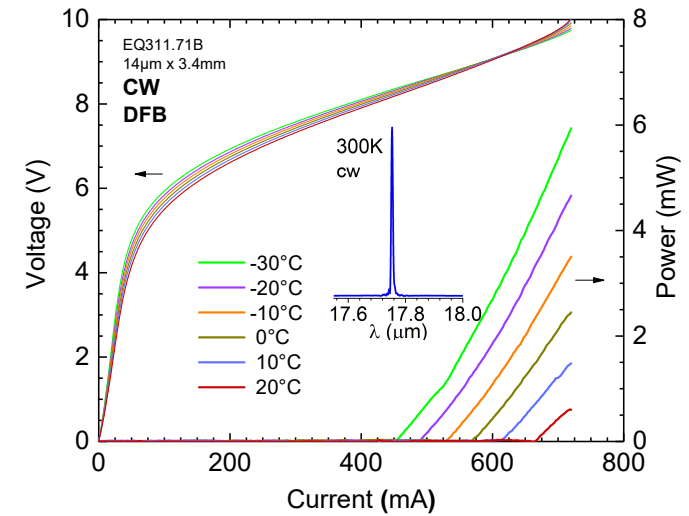
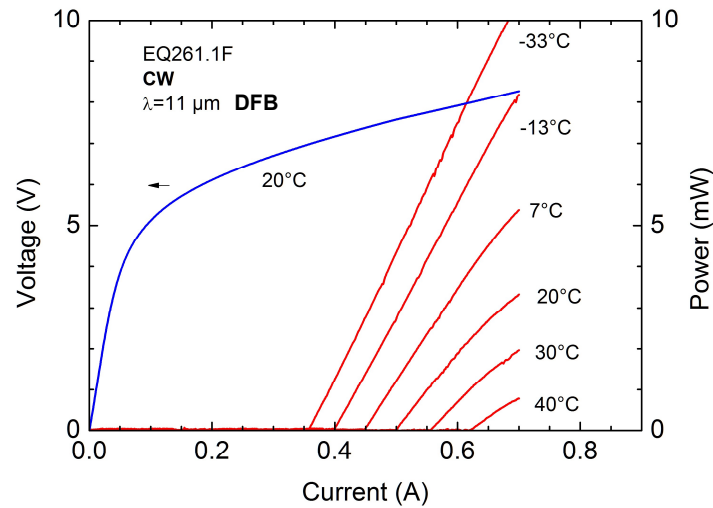


Gain in QCL

$$g \propto \frac{1}{m^*{}^{3/2}}$$



# Long wavelength InAs/AlSb QCLs: state of the art



**$T_{\text{max}}$  continuous wave**

**40°C at  $\lambda = 11\ \mu\text{m}$**

**20°C at  $\lambda = 15\text{-}18\ \mu\text{m}$**

**-30°C at  $\lambda = 20\ \mu\text{m}$**

**$J_{\text{th}} \sim 1\ \text{kA/cm}^2$  at RT**

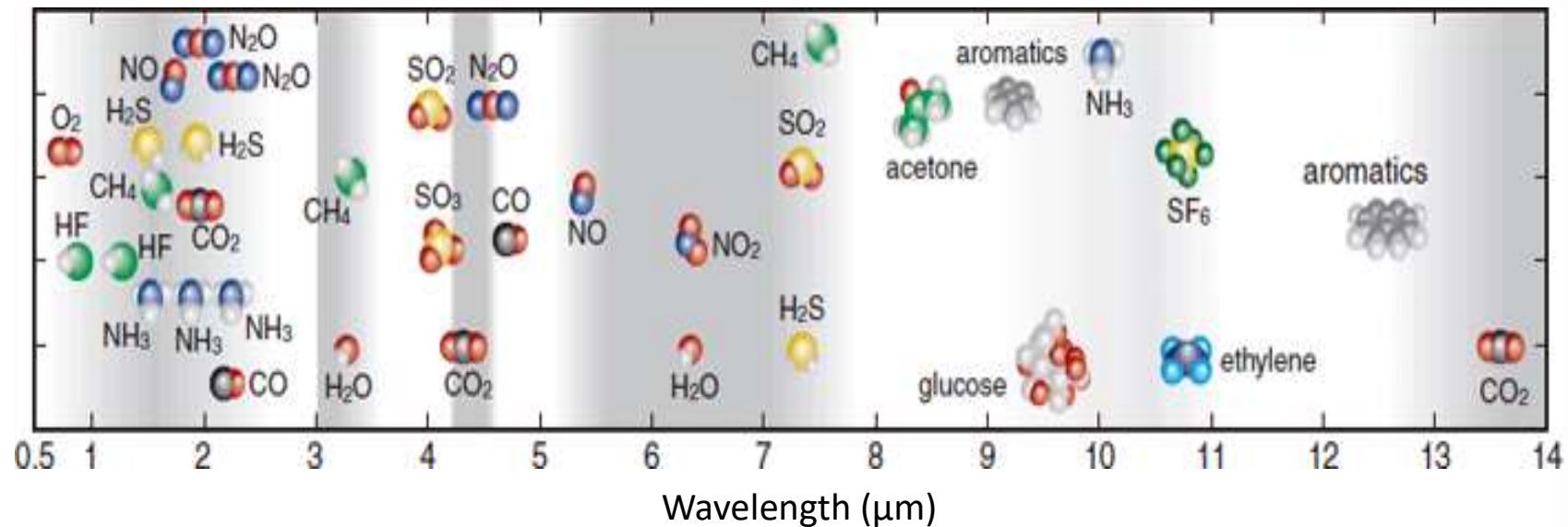
**$\lambda_{\text{max}}$  25.5  $\mu\text{m}$  (pulsed)**

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- InAs/AlSb quantum cascade lasers: properties
- Integration on Si: motivations
- Molecular-beam epitaxy on Si
- Laser properties
- Summary – Perspectives

# The sensing challenge

www.daylightsolutions.com



**Mid-IR: atmosphere transparency windows + “fingerprint” region**

## A wealth of applications

Atmospheric pollution monitoring, industrial process control, food industry, health, security, free space optics, etc.

**Increasing demand for low-cost, small footprint, smart, photonic sensors.**

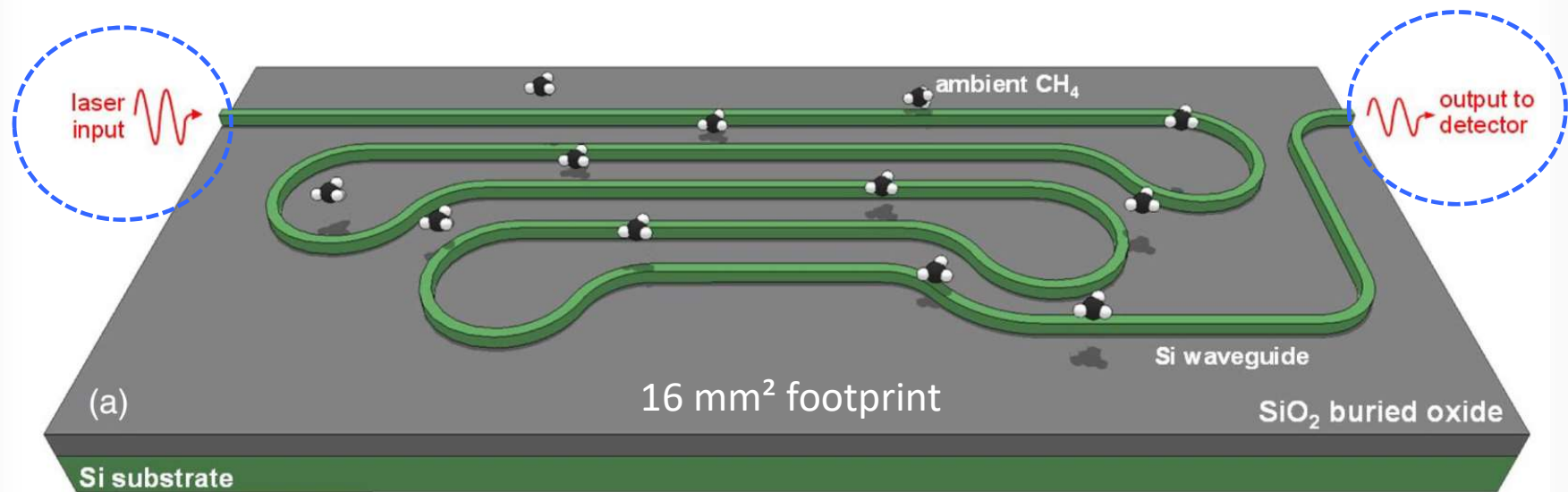
# The sensing challenge

## Methane absorption spectroscopy on a silicon photonic chip

Tombez *et al.*, IBM TJ Watson Res. Center

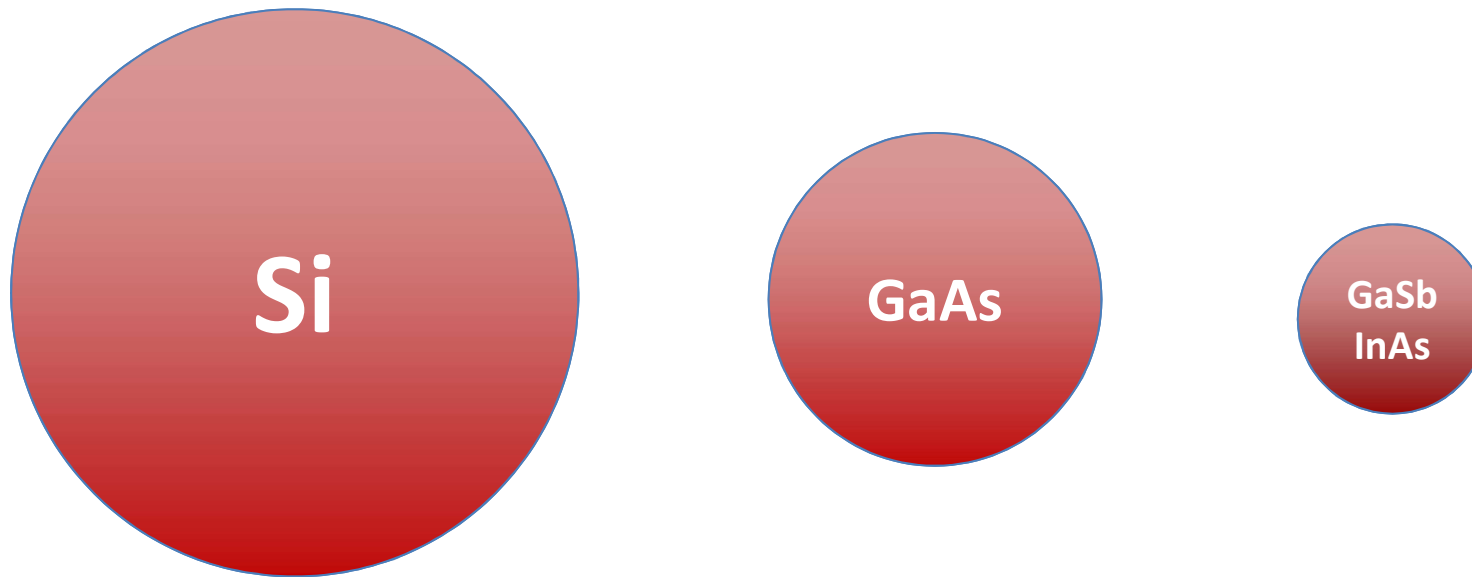
Vol. 4, No. 11 / November 2017 / *Optica*

1322



**Need for integrated opto devices**

## The substrate challenge



|                    | Si  | GaAs | InP | GaSb/InAs |
|--------------------|-----|------|-----|-----------|
| Diameter (mm)      | 300 | 175  | 100 | 100       |
| \$/cm <sup>2</sup> | 0.5 | 2    | 6   | 12        |

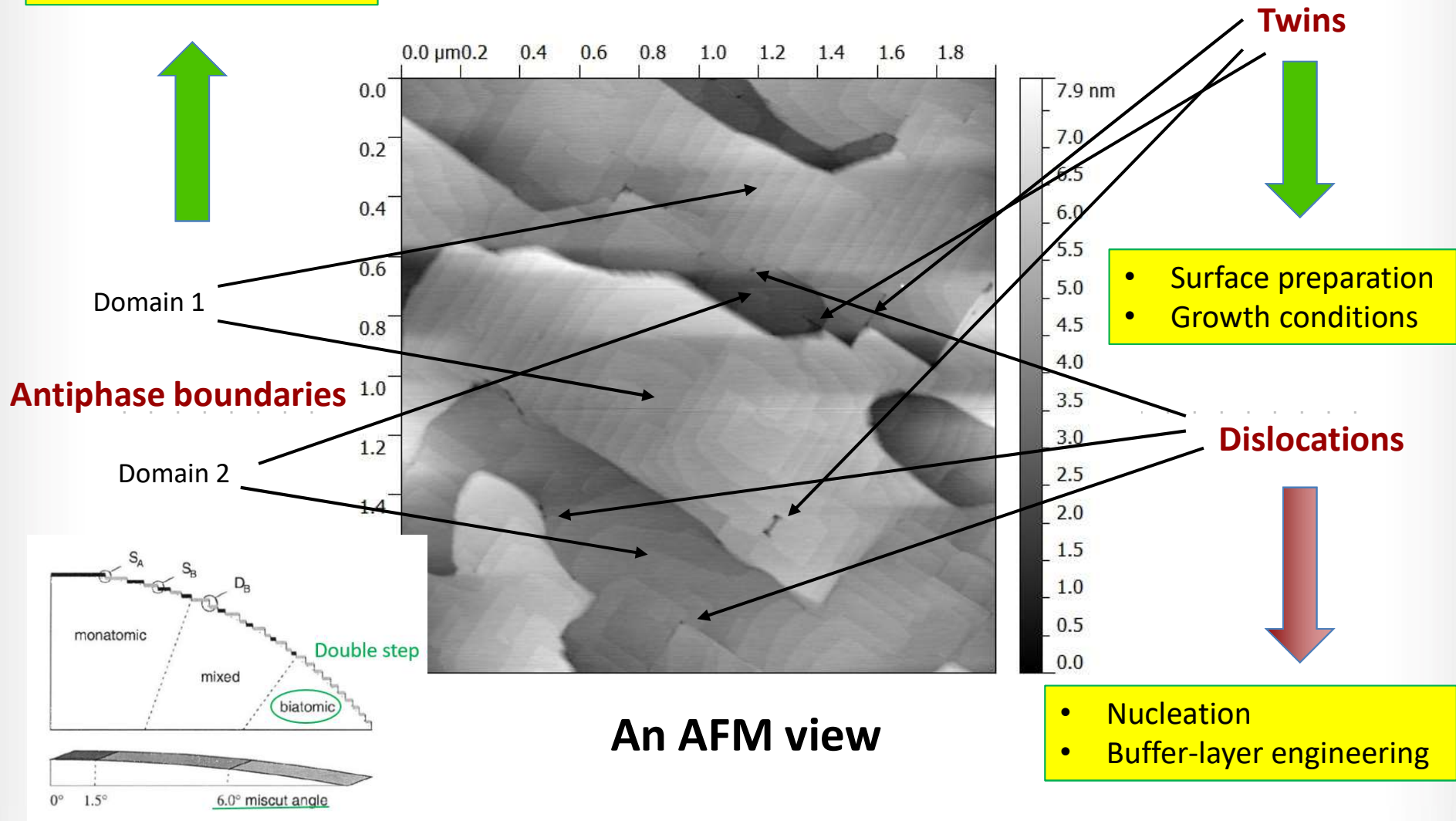
Low cost mid-IR devices → Si platform.

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- **Molecular-beam epitaxy on Si**
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## III-V epitaxy on Si: a number of mismatches

- Surface preparation
- Off-cut substrates



- Surface preparation
- Growth conditions

- Nucleation
- Buffer-layer engineering

Dislocations **cannot be avoided**, but their threading density can be reduced

# Epitaxial growth on Si: experimental

## Si substrates

- 4 – 6° offcut (001) 2 inch. Si substrates

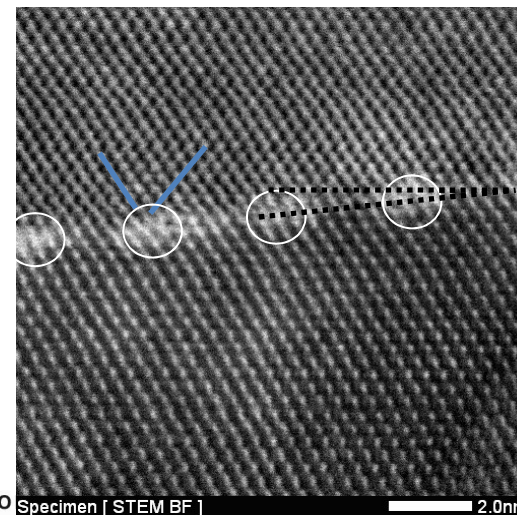
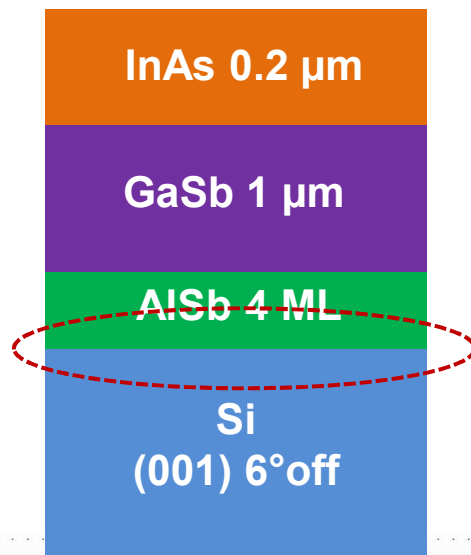
## Standard III-V molecular-beam epitaxy (MBE) reactor

- Solid-source MBE with load-lock chamber
- Valved-cracker cells for As and Sb
- Standard group-III effusion cells
- $T_{\text{substrate}} < 850\text{ }^{\circ}\text{C}$

- Growth chamber and  $T_{\text{substrate}}$  not compatible with *in-situ* Silicon de-oxidation
- No Si buffer-layer growth in (most) III-V systems

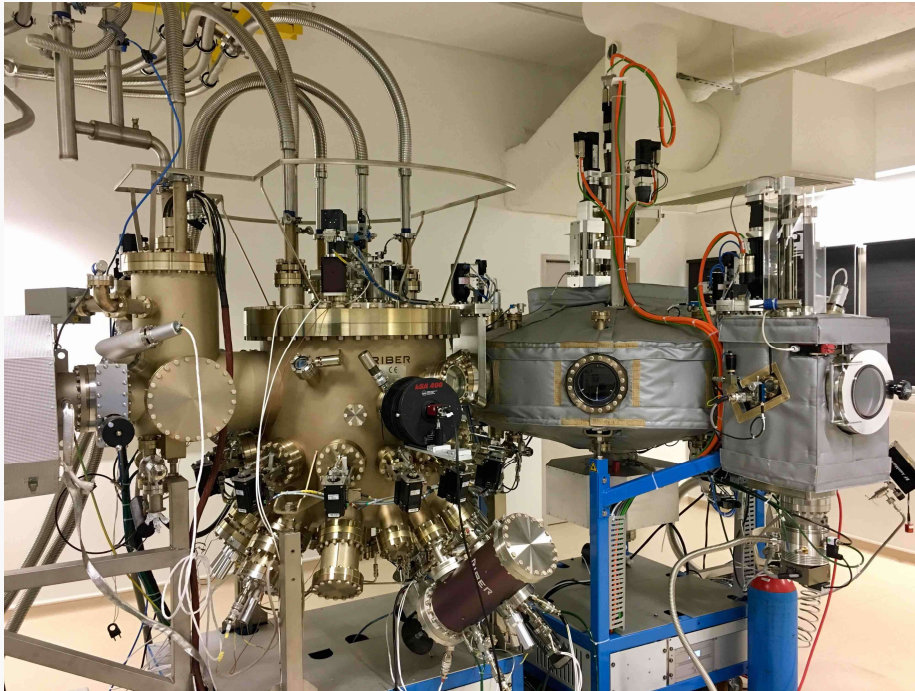
## InAs/GaSb on Si templates

- 4 – 6° off (001)Si
- *Ex-situ* O<sub>2</sub> Plasma + HF Si preparation cycles
- *In-situ* annealing at 800°C
- 4 MLs AlSb @ 450°C
- ~ 1 µm GaSb buffer layer
- 200 nm InAs



TEM image: A. Trampert, PDI-Berlin

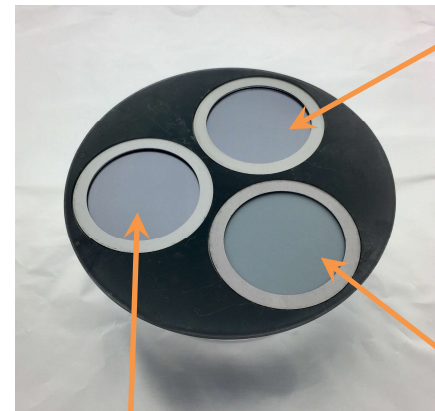
# MBE growth



**RIBER 412 MBE system**

**Substrate 2"n-InAs (100)**

**InAs**



**Dummy**

**Template on 2" Si (100) 6°off**

**InAs 0.2  $\mu\text{m}$**

**GaSb 1  $\mu\text{m}$**

**AlSb 4 ML**

**Si  
(100) 6°off**

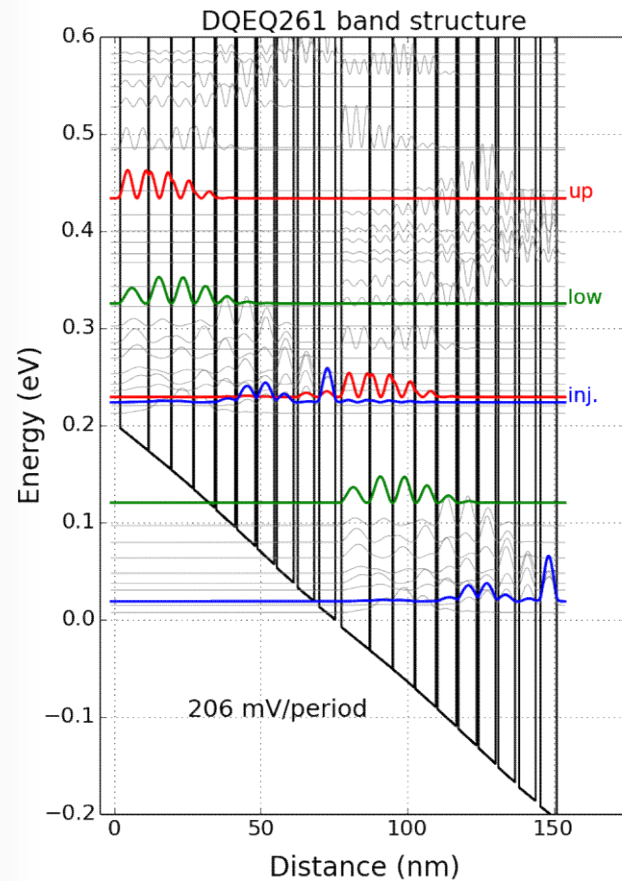
**Side-by-side growth on 2 substrates**

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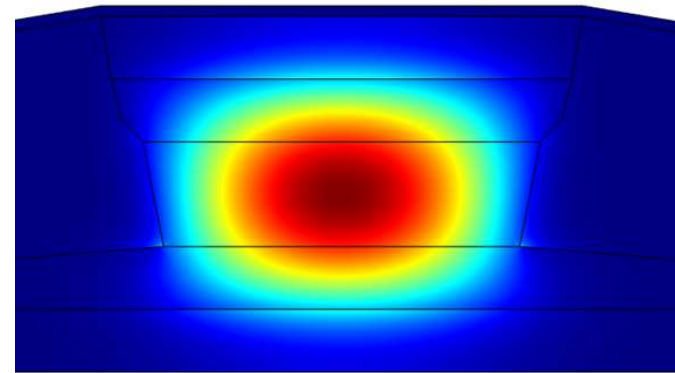
# QCL structure

## Design



**Four quantum wells**  
**Vertical transitions**

## Waveguide

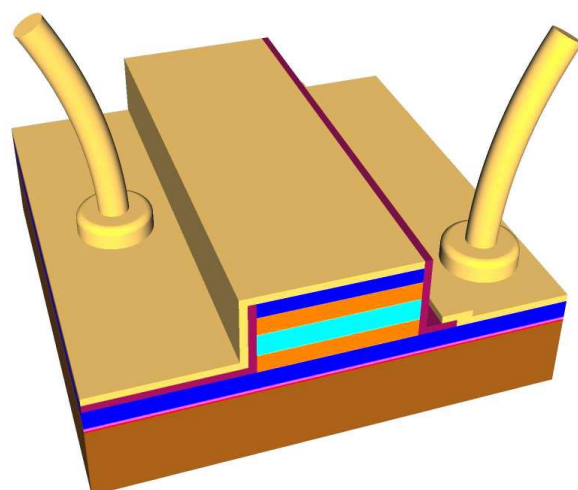
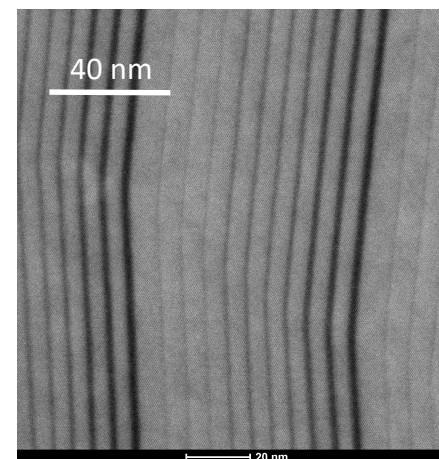
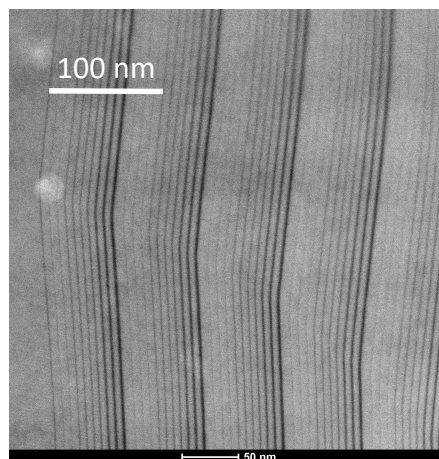
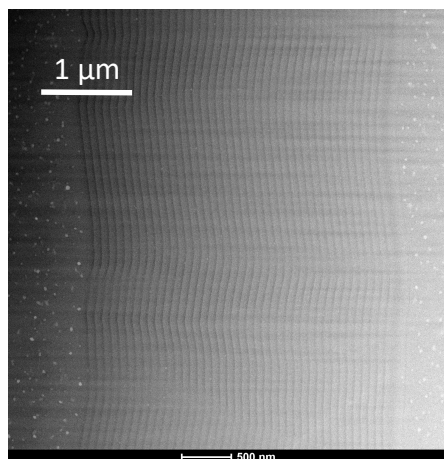


|                                           |        |
|-------------------------------------------|--------|
| Cladding n <sup>+</sup> InAs              | 2 μm   |
| Spacer n-InAs                             | 2.5 μm |
| QCL active region                         | 3 μm   |
| Spacer n-InAs                             | 2.5 μm |
| Cladding n <sup>+</sup> InAs              | 2 μm   |
| Substrate n-InAs OR InAs/GaSb/Si template |        |

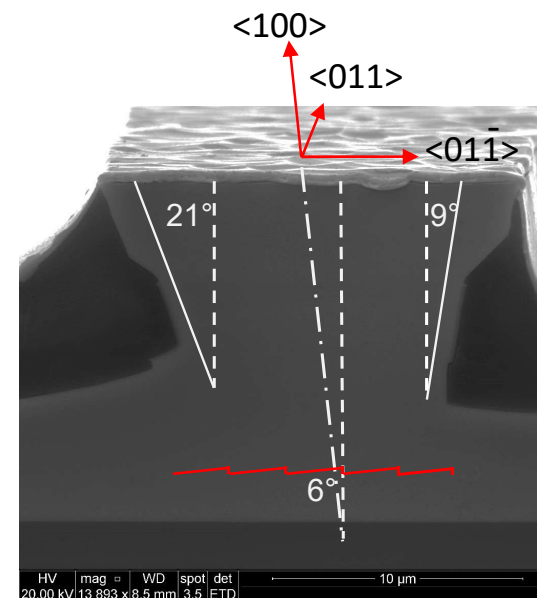
$$\Gamma = 0.56$$

**Designed to emit at 11 μm**

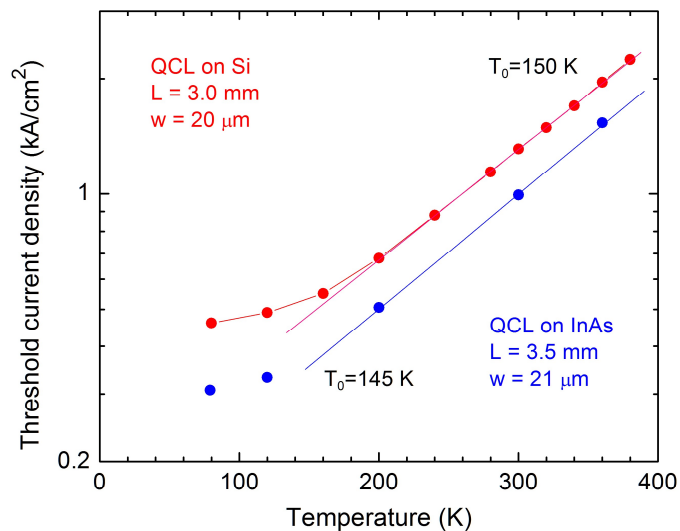
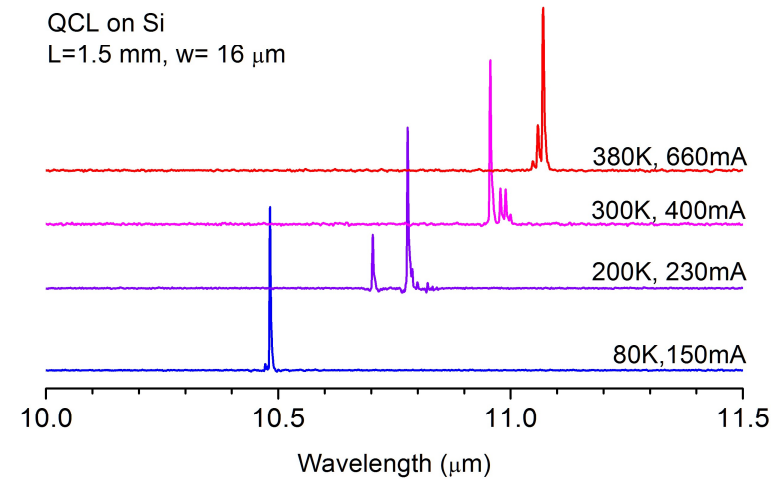
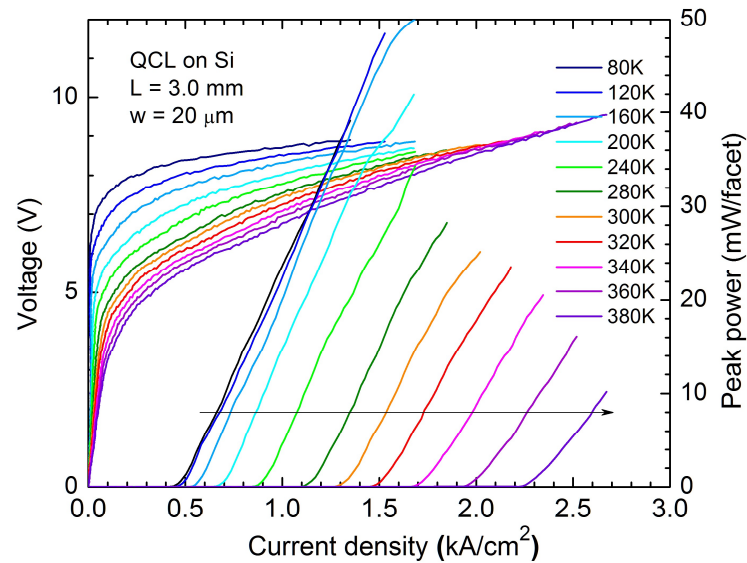
# InAs/AlSb QCL on Si



- Au contacts
- hard baked photoresist
- n<sup>+</sup>-InAs top cladding
- n<sup>+</sup>-InAs top spacer
- InAs/AlSb active zone
- n<sup>+</sup>-InAs bottom spacer
- n<sup>+</sup>-InAs bottom cladding
- GaSb template
- Si substrate

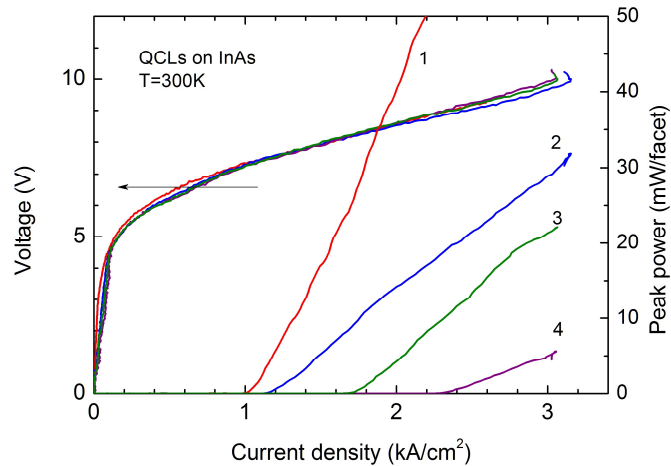


# InAs/AlSb QCL on Si



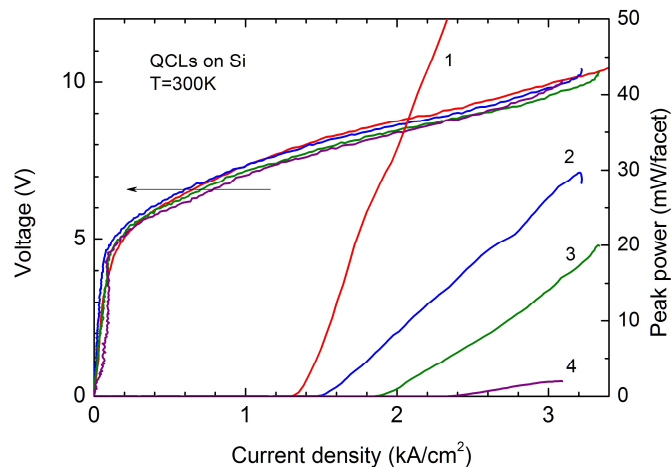
**First-ever report of a QCL grown on Si**

# InAs/AlSb QCL on Si



InAs substrate:

1.  $L = 3.5$  mm,  $w = 21$   $\mu\text{m}$
2.  $L = 2.3$  mm,  $w = 14$   $\mu\text{m}$
3.  $L = 1.2$  mm,  $w = 17$   $\mu\text{m}$
4.  $L = 0.7$  mm,  $w = 17$   $\mu\text{m}$

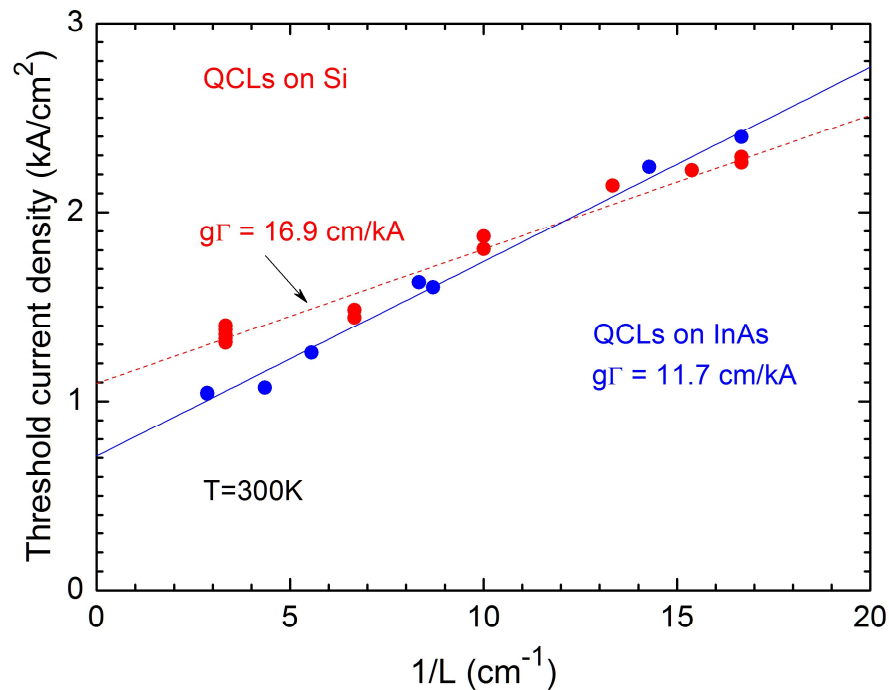


Si substrate:

1.  $L = 3.0$  mm,  $w = 20$   $\mu\text{m}$
2.  $L = 1.5$  mm,  $w = 16$   $\mu\text{m}$
3.  $L = 1.15$  mm,  $w = 15$   $\mu\text{m}$
4.  $L = 0.6$  mm,  $w = 14$   $\mu\text{m}$

**Performances are similar on InAs and on Si substrates!!!**

## QCLs on Si vs QCLs on InAs



$$J_{th} = J_{tr} + \frac{(\alpha_w + \alpha_m)}{\Gamma g}$$

$$J_{th} = J_{tr} + \frac{\alpha_w}{\Gamma g} - \frac{\ln(R)}{\Gamma g} \frac{1}{L}$$

### QCL on InAs

$$g\Gamma = 12 \text{ cm/kA}$$

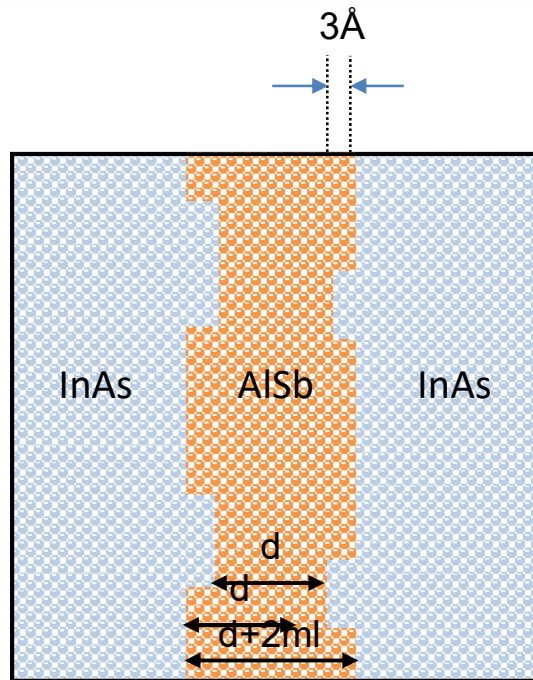
### QCL on Si

$$g\Gamma = 17 \text{ cm/kA}$$

$$\Gamma = 0.56 \text{ optical confinement}$$

**Higher gain in QCLs grown on Si**

## QCLs on Si – why so good?



On-axis perfect interfaces: 1 ML (3Å) roughness

**Step flow growth on 6°-off substrate**

**Low interface scattering due to misoriented substrate**

$$g = \frac{e\hbar}{\epsilon_0 c m_0} \frac{1}{2\gamma_{32} n L_p} f_{32} \tau_3 \left( 1 - \frac{\tau_2}{\tau_{32}} \right)$$

$\tau_3$  upper level lifetime

$\tau_3 = 0.42$  ps (LO-phonon emission)

$$\frac{1}{\tau_3} = \frac{1}{\tau_{32}} + \frac{1}{\tau_{31}} + \frac{1}{\tau_i}$$

high barriers  $\rightarrow$  strong interface recombination

$$\frac{1}{\tau_i} \sim (\Delta E_c)^2$$

$\tau_3 = 0.3$  ps with interface scattering

# OUTLINE

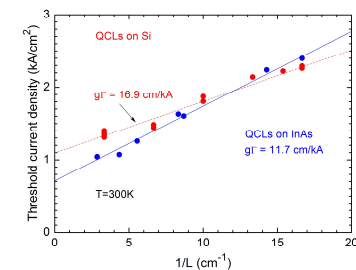
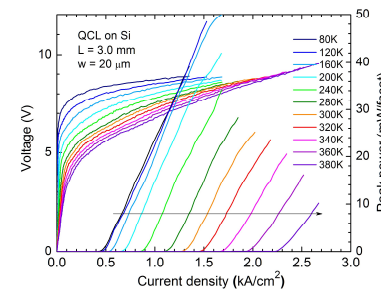
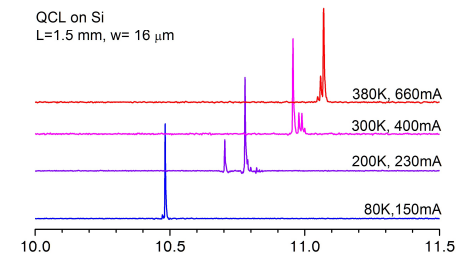
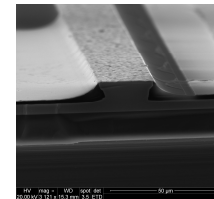
- InAs/AlSb quantum cascade lasers: properties
- Integration on Si: motivations
- Molecular-beam epitaxy on Si
- Laser performances
- **Summary – Perspectives**

# Summary

Quantum cascade laser is a very robust technology

First quantum cascade lasers grown on silicon

- $\lambda = 11 \mu\text{m}$
- Low threshold :  $1.3 \text{ kA/cm}^2$
- High temperature operation: 400K
- No significant performance degradation
- InAs/AlSb QCLs: from 3 to  $25 \mu\text{m}$

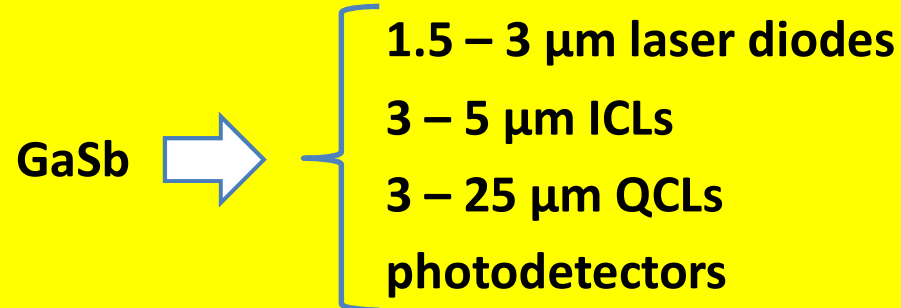


## Perspectives

- Further work on templates, toward on-axis substrates
- Dislocation filtering
- Optimized device design and technology

### Future

**A complete IR optoelectronics toolbox integrated on Silicon**



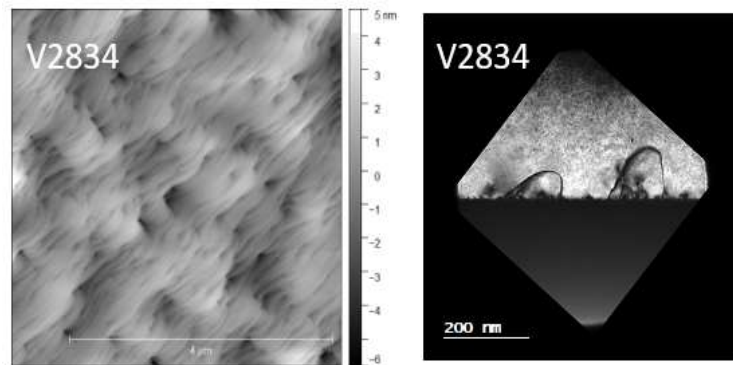
**Development of a variety of Mid-IR integrated sensors**

## Toward on-axis Si: an AFM view

500 nm GaSb on 0.5° offcut (001) Si

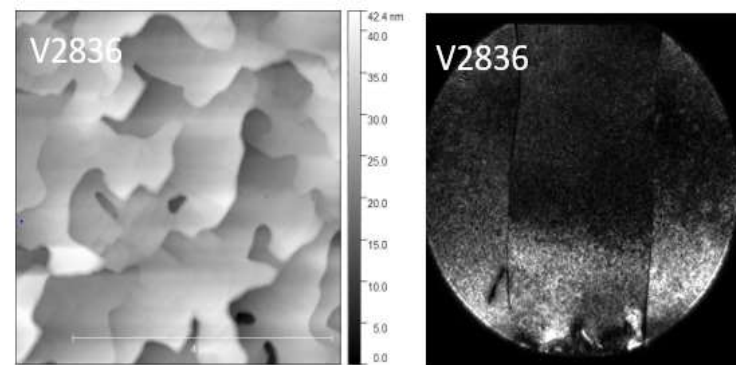
5 x 5  $\mu\text{m}^2$  AFM images + TEM

Improved template



APD free

Original template



60%/40% domain distribution

**APD free down to 0.5° miscut**

# Aknowledgments



**Equipex EXTRA**

*ANR-11-EQPX-0016*



**FEDER – grants 47851 & 49793**



## Thank you for your attention!

